

Morphological evolution of SiGe nanostructures

I. Berbezier, A. Ronda

L2MP – CNRS

University Paul Cézanne,
Marseille



Laboratoire Matériaux et Microélectronique de Provence

OUTLINE

Introduction

Morphological evolution of SiGe layers on :

*** Si(111)**

*** Si(001)**

Conclusion

CONFIGURATIONAL FORCE

= Gradient in μ

Isothermal ($T_{sub} = T_{res}$), Isobaric ($P_{sub} = P_{res}$) subsystem
 → $G_{subsystem}$ minimized in equilibrium

$$dG = -SdT + VdP + \mu dN$$

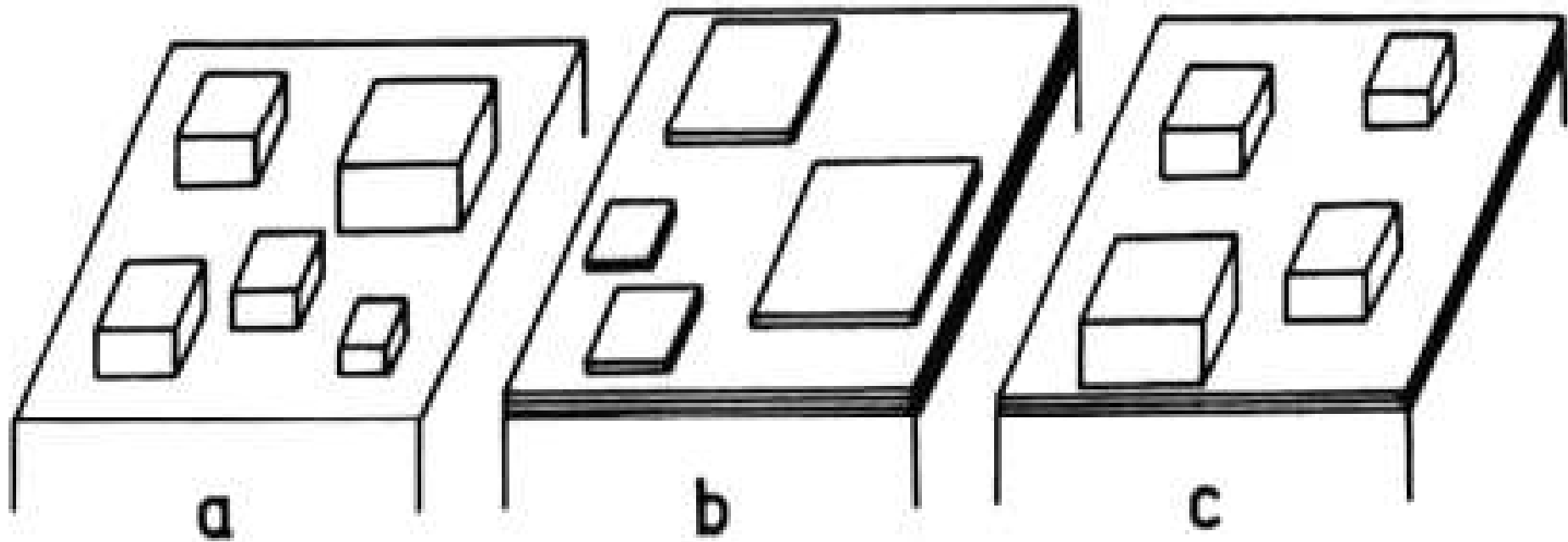
$$\mu \equiv \left(\frac{\partial G}{\partial N} \right)_{T,P}$$

Solid phase “ β ”, single component, surrounded by phase “ α ”:

$$\mu^\beta = \underbrace{\mu_{\text{stress-free bulk}}^\beta(T)}_{\text{Term 1: depends on phase: bonding, etc.}} + \underbrace{\frac{1}{2} \mathbf{C}^\beta \boldsymbol{\varepsilon}^2}_{\text{Term 2: elastic strain energy density}} - \underbrace{\sigma_{\text{normal}} \Omega^\beta}_{\text{Term 3: PV work to push surroundings out of the way}} + \underbrace{\left[\left(\gamma^{\alpha\beta} + \frac{d^2 \gamma^{\alpha\beta}}{d\theta_1^2} \right) \frac{1}{R_1} + \left(\gamma^{\alpha\beta} + \frac{d^2 \gamma^{\alpha\beta}}{d\theta_2^2} \right) \frac{1}{R_2} \right] \Omega^\beta}_{\text{Term 4: total surface energy (including anisotropy)}}$$

Ω = atomic (or molecular) volume
 R = principal radius of curvature
 θ = surface orientation

GROWTH MODES



Volmer Veber
or island growth

$$d\mu / dn < 0$$

Frank van der Merwe
or layer by layer growth

$$d\mu / dn > 0$$

Stranski Krastanov
or layer by layer growth
followed by 3D islands

$$d\mu / dn > / < 0$$

During epitaxy

Strain energy

Surface energy

$$\mu^\beta = \underbrace{\mu_{\text{stress-free bulk}}^\beta(T)}_{\text{Term 1: depends on phase: bonding, etc.}} + \underbrace{\frac{1}{2} \mathbf{C}^\beta \boldsymbol{\varepsilon}^2}_{\text{Term 2: elastic strain energy density}} - \underbrace{\sigma_{\text{normal}} \Omega^\beta}_{\text{Term 3: PV work to push surroundings out of the way}} + \underbrace{\left[\left(\gamma^{\alpha\beta} + \frac{d^2 \gamma^{\alpha\beta}}{d\theta_1^2} \right) \frac{1}{R_1} + \left(\gamma^{\alpha\beta} + \frac{d^2 \gamma^{\alpha\beta}}{d\theta_2^2} \right) \frac{1}{R_2} \right]}_{\text{Term 4: total surface energy (including anisotropy)}} \Omega^\beta$$

Ω = atomic (or molecular) volume
 R = principal radius of curvature
 θ = surface orientation

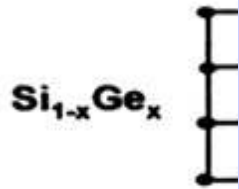
Stranski-Krastanov growth mode : 2 critical thickness

Misfit $\varepsilon = \Delta a / a = 4.2 \%$

$a_{\text{Si}} = 5.4311 \text{ \AA}$

$a_{\text{Ge}} = 5.6579 \text{ \AA}$

$$h_{\text{cr}} / H_{\text{cr}}$$



h_{cr}



Strain energy

H_{cr}



Chemical potential

Comparison (111) and (001)

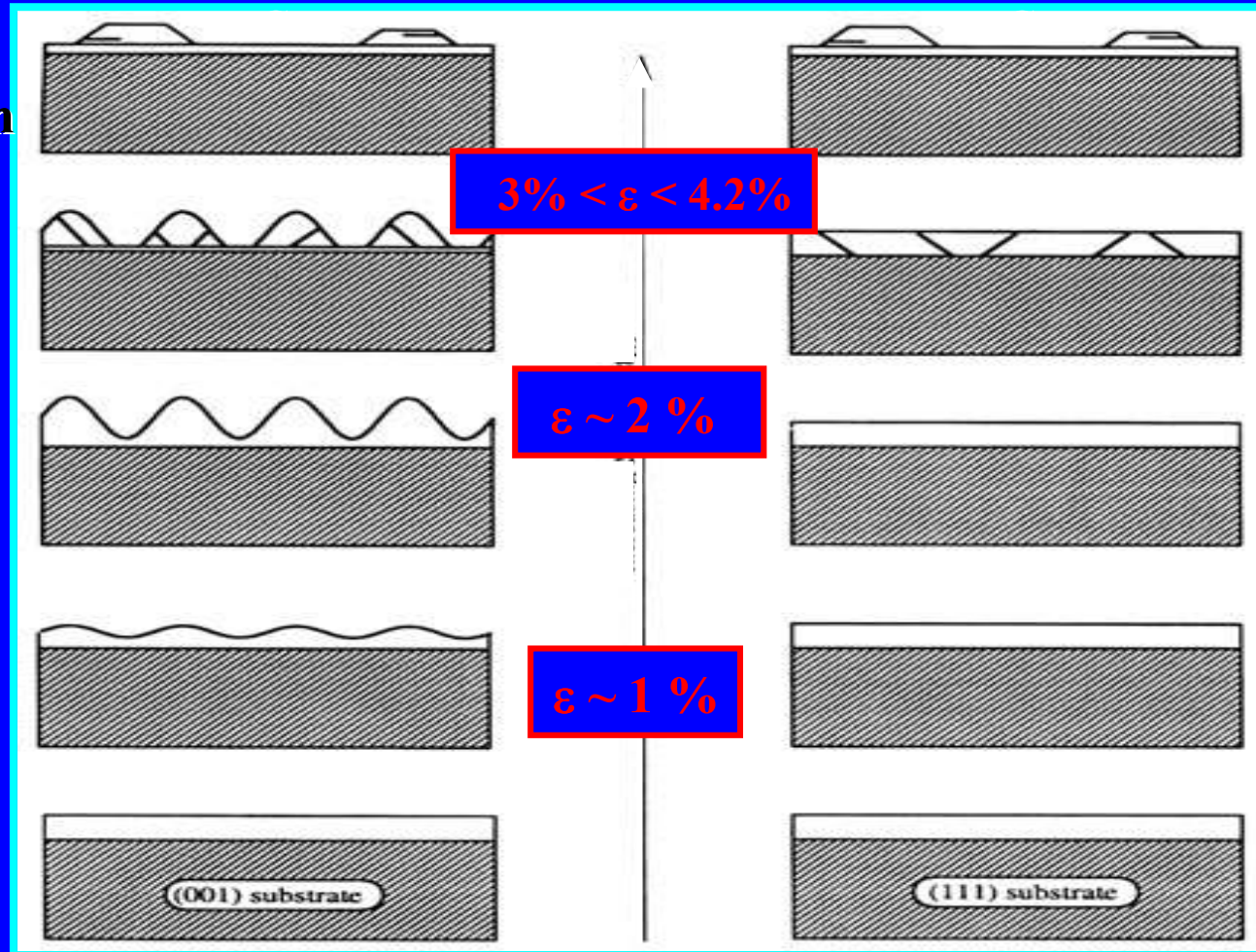
S-K growth mode
with Plastic relaxation

Kinetic
growth instability
only on (001)

2D nucleation
layer by layer

(001)

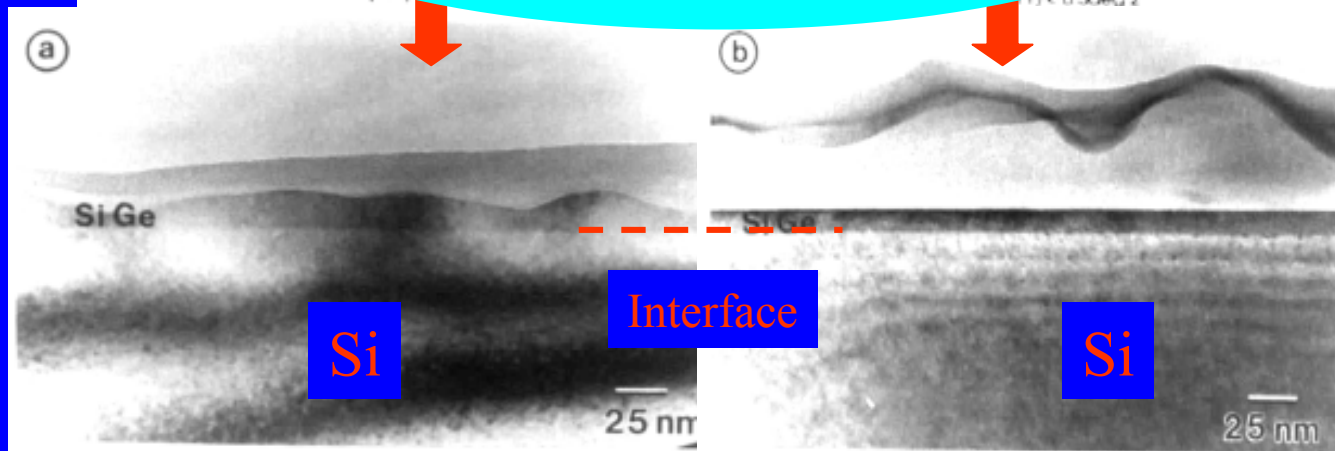
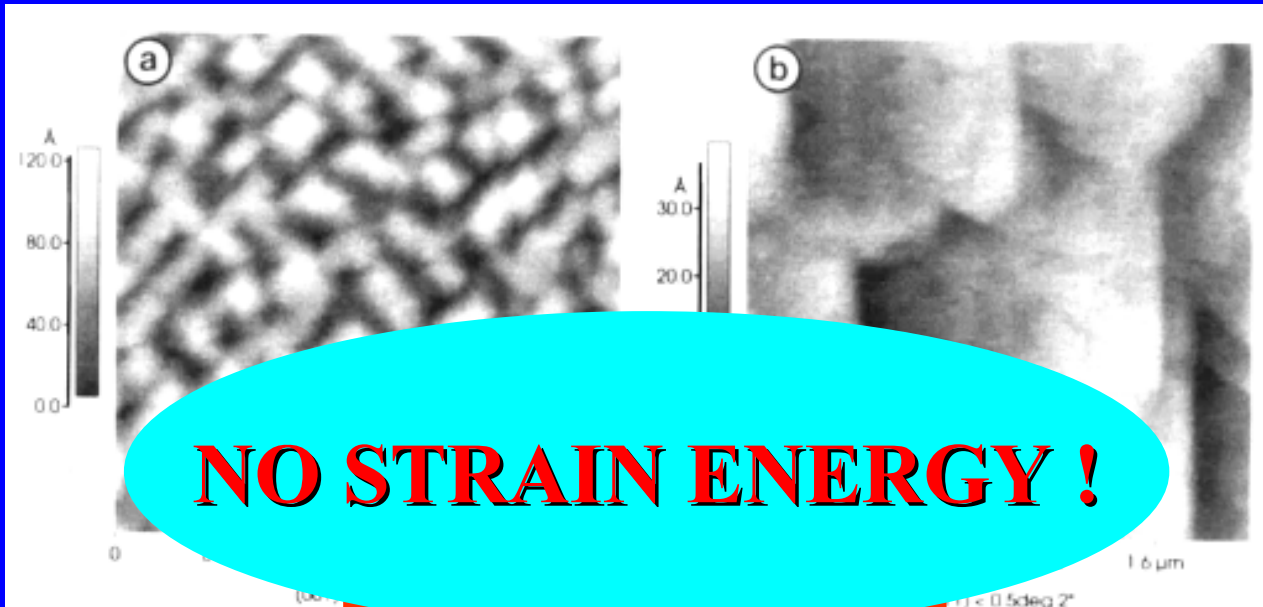
(111)



WHY ?

(001)
Growth instability

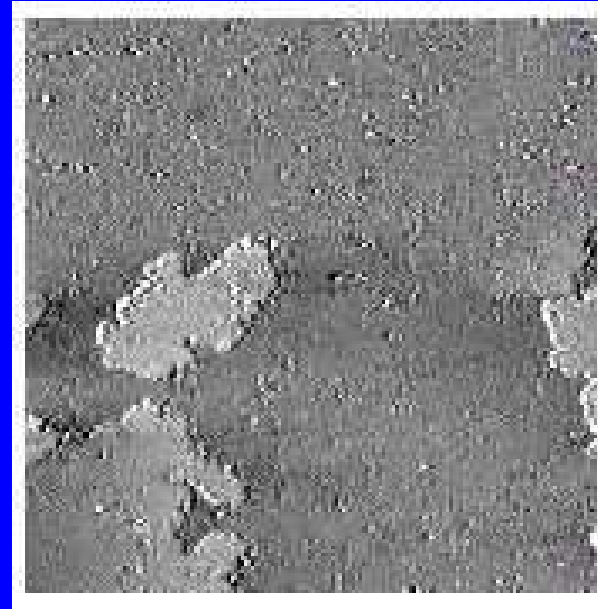
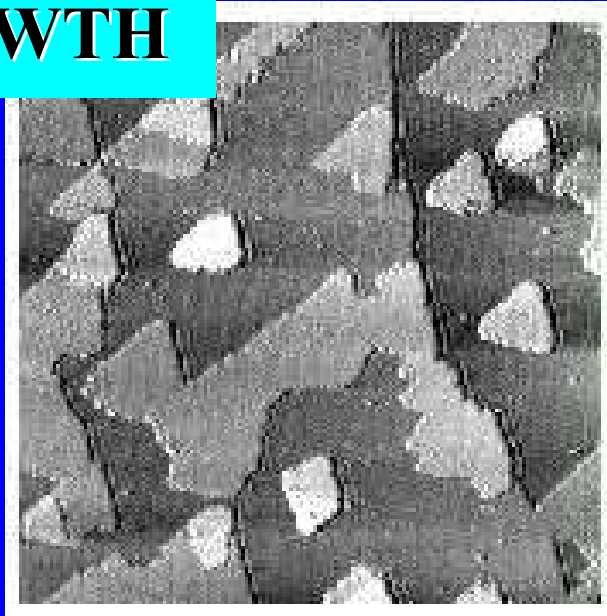
(111)
Layer by layer growth



GROWTH OF SiGe ON Si(111)

REGIME I: 2D GROWTH

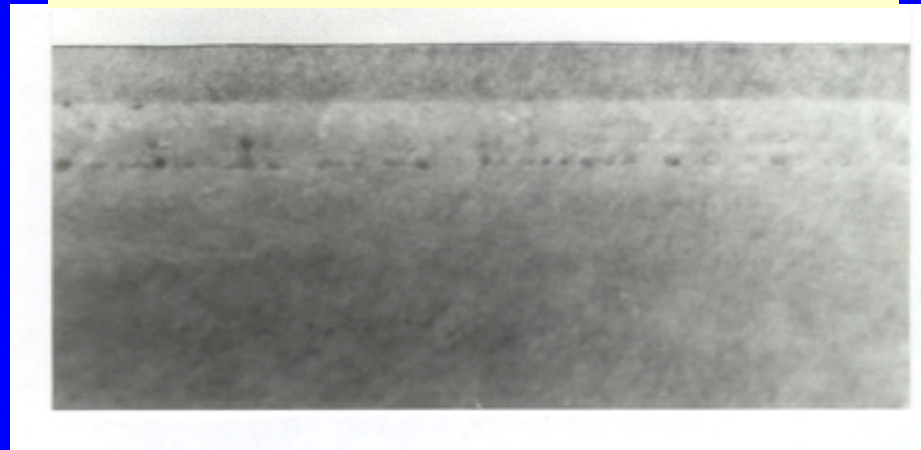
2D nucleation



B. Voigtländer et al., Review of Scientific Instruments 67 (1996) 2568.

T_G

Step flow layer by layer growth



I. Berbezier et al., Surf. Sci. 412/413 (1998) 415

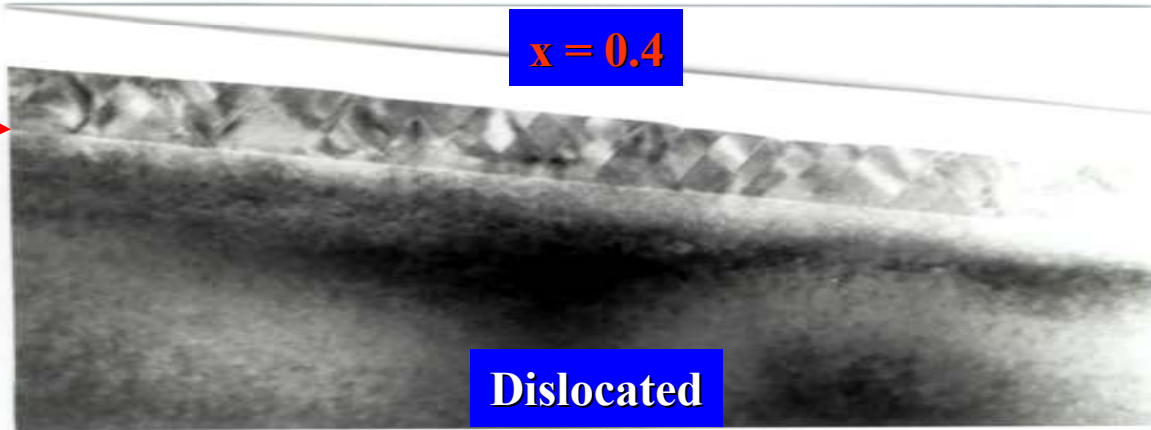
REGIME II: 3D GROWTH



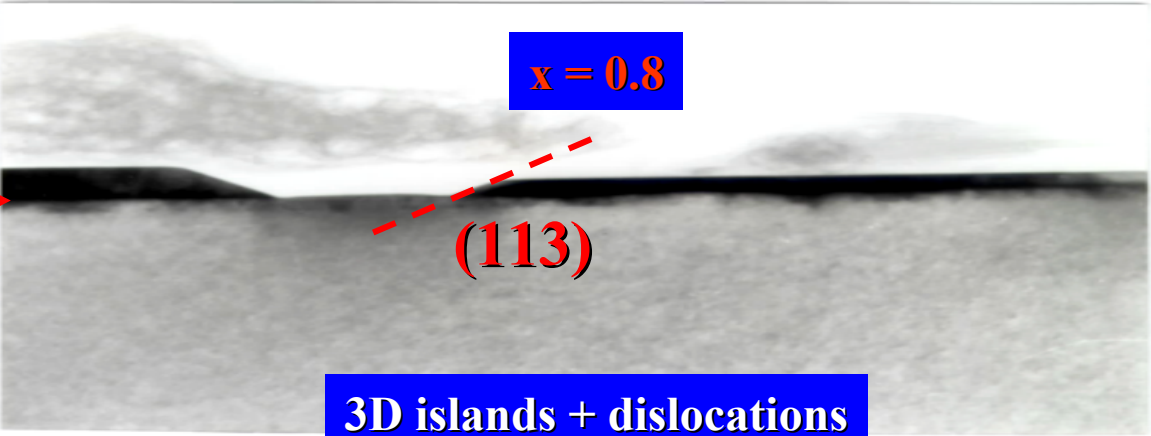
$x = 0.15$



$x = 0.4$



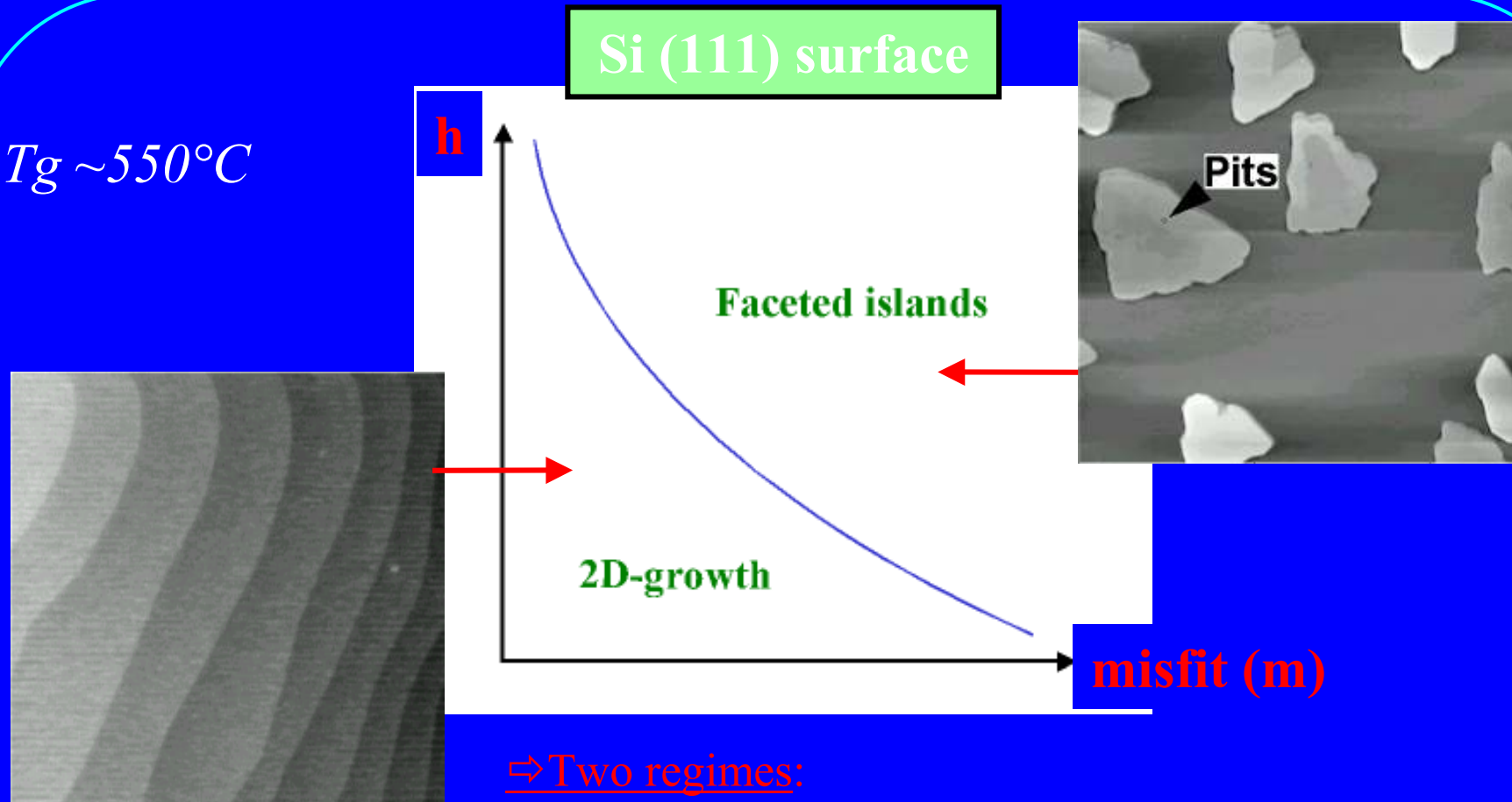
$x = 0.8$



Increasing stress

Morphological Evolution of SiGe Layers: *Experimental « kinetic » phase diagrams, Si(111)*

$T_g \sim 550^\circ\text{C}$



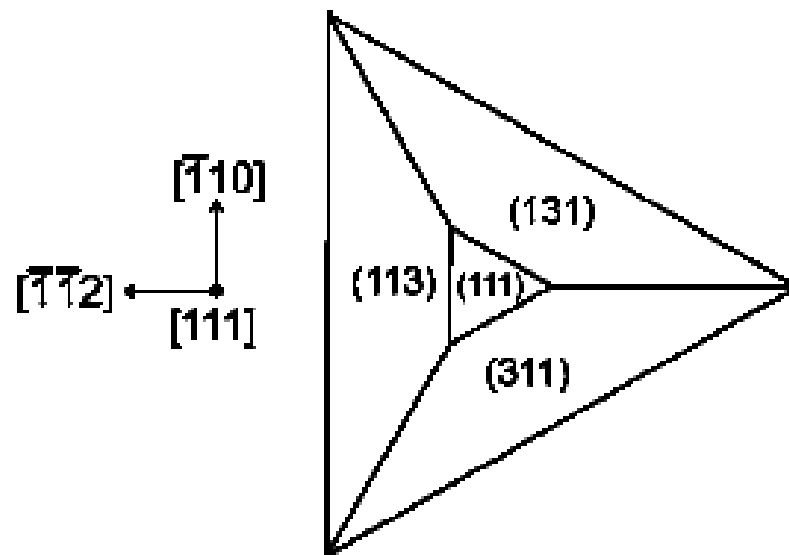
⇒ Two regimes:

- 2D layer by layer at low (h,m)
- Classical SK growth (dislocated islands) at high (h,m)

Equilibrium shape of Ge / Si

$$E_{\text{total}} = E_{\text{elastic}} + E_{\text{surface}} + E_{\text{edge}}$$

$$F_{\text{a}} = \frac{s\gamma_{\text{side}}}{\cos \theta} \left(\frac{3}{sm \tan \theta} V \right)^{2/3} (1 - \epsilon^3)^{1/3}$$



Corresponds to the experimental results

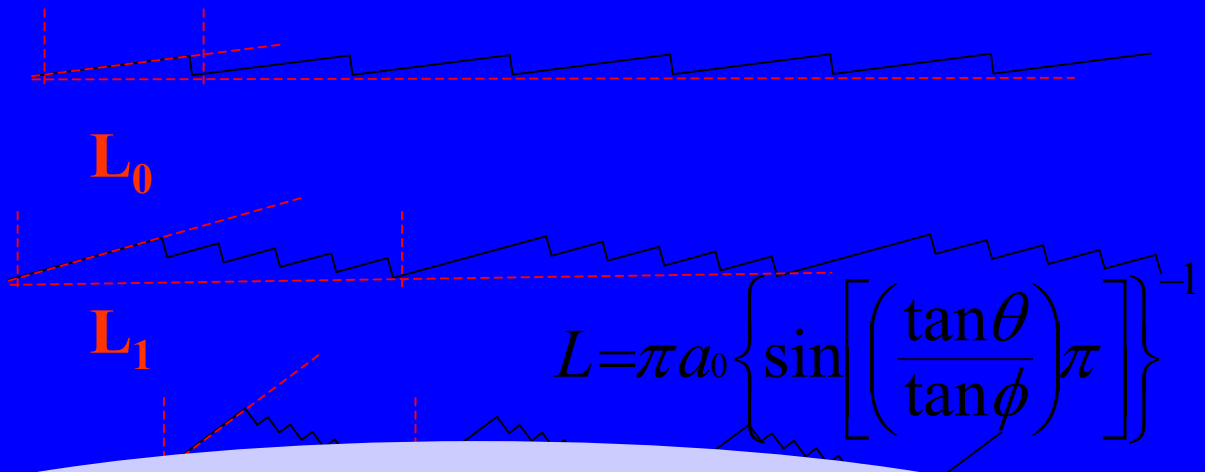
A. A. Stekolnikov and F. Bechstedt, PHYS. REV. B 72, 2005

INFLUENCE OF VICINAL SUBSTRATE

Scan size : 2 μm

ML steps

0° off



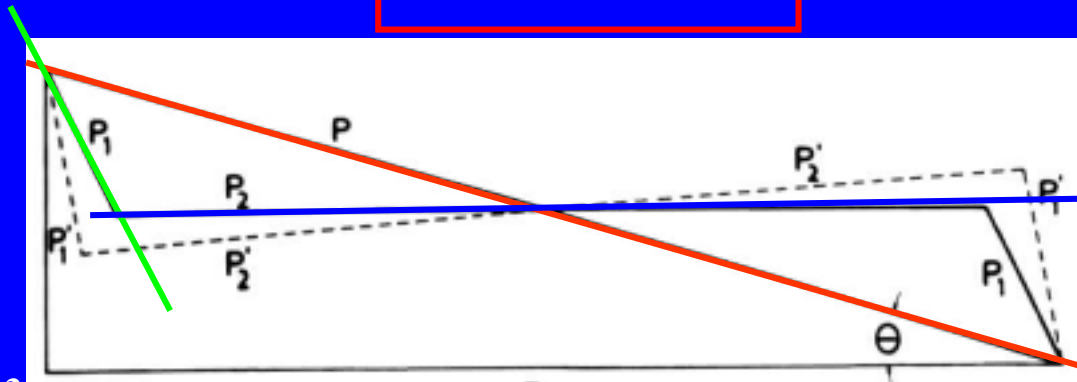
2 = Equilibrium shape of Ge / Si

Condition of stability : surface stiffness of $p > 0$

$$\sigma^* = \sigma + \frac{d^2\sigma}{d\theta^2} > 0$$

Step bunching

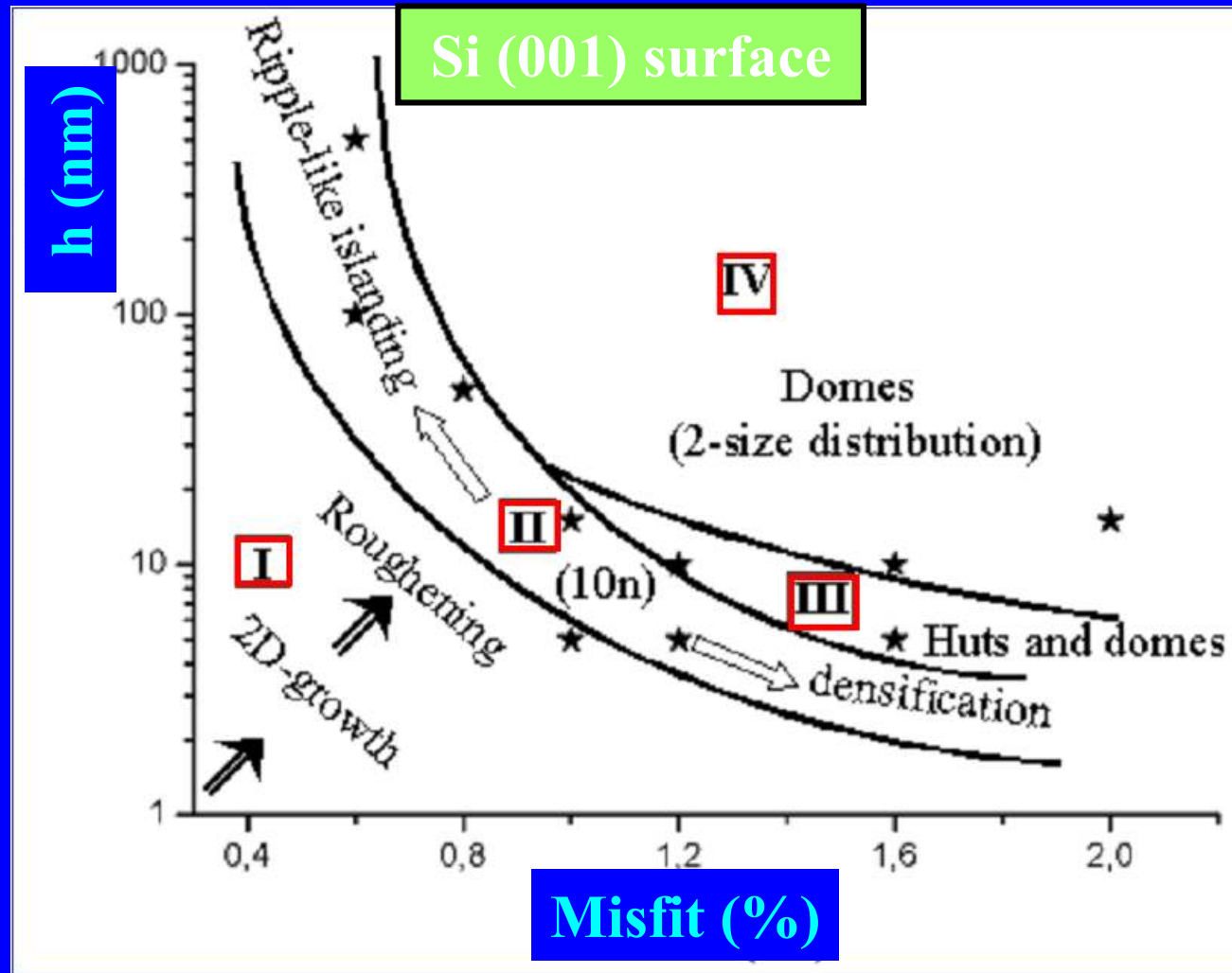
0° off



$h = 10 \text{ nm}$ $x = 0.3$

GROWTH OF SiGe ON Si(001)

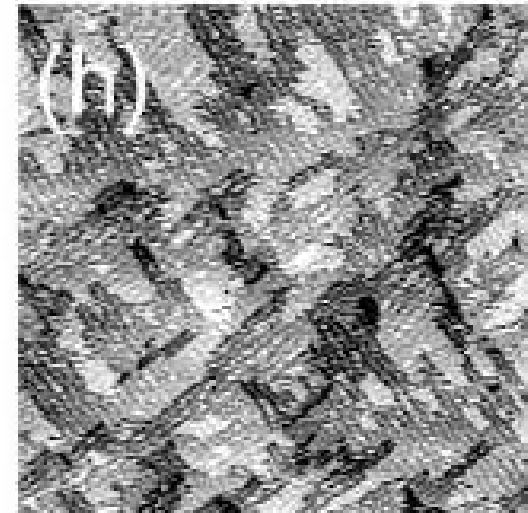
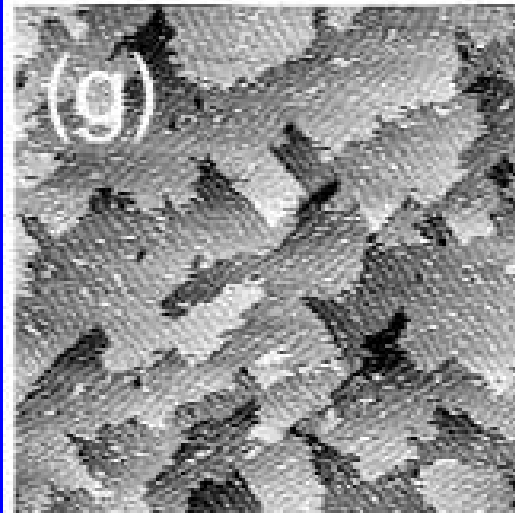
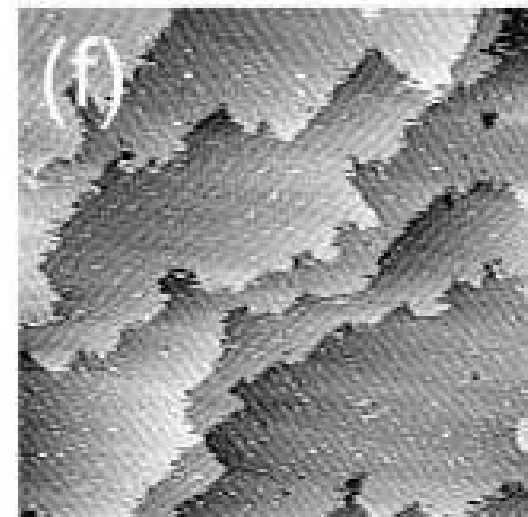
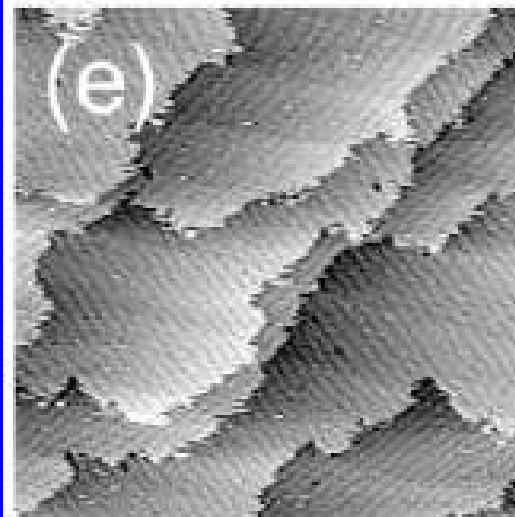
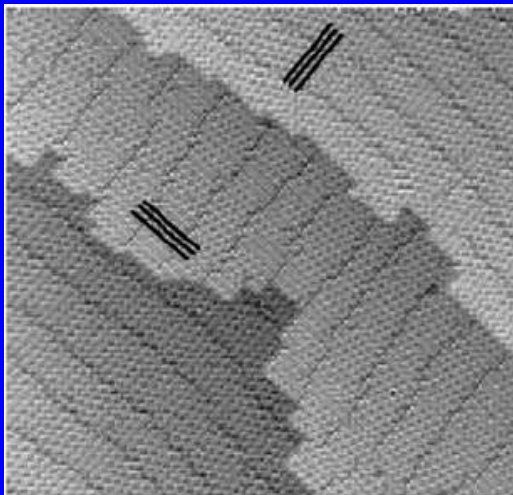
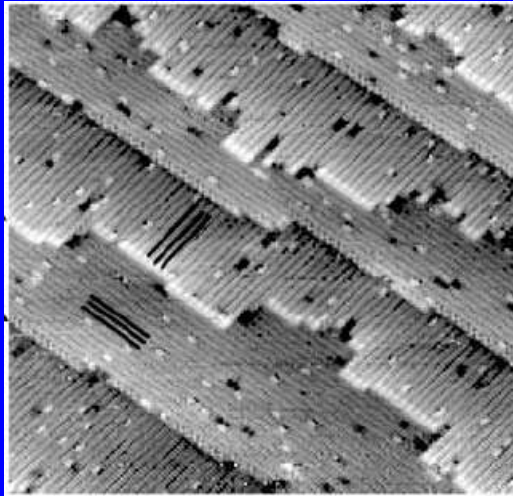
Morphological Evolution of SiGe Layers: *Experimental kinetic phase diagrams, Si(001)*



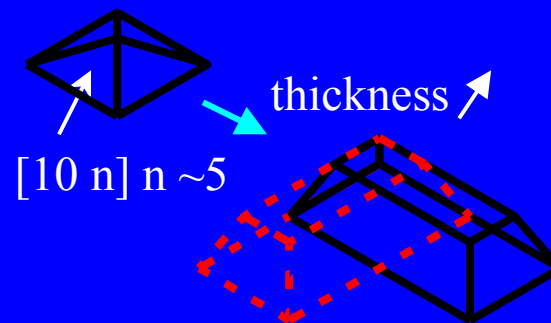
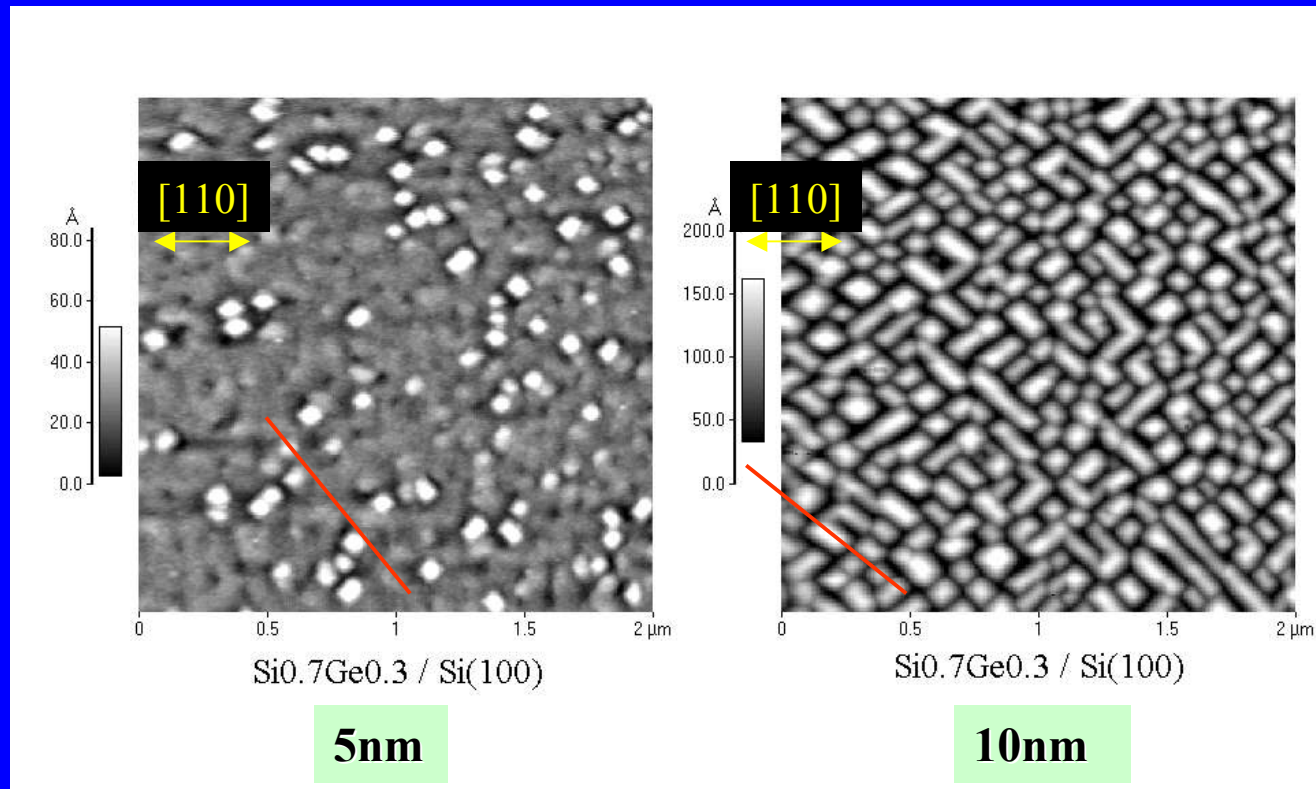
➔ 4 growth regimes

REGIME I: ROUGHENING

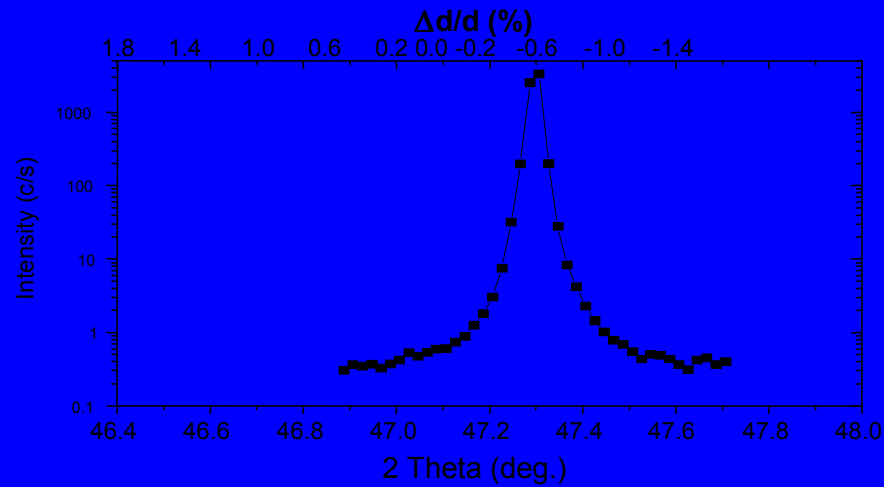
Remains flat during annealing



REGIME II : HUTS ISLANDS



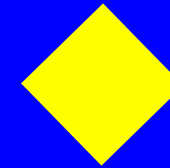
Stress Relaxation : *XRD analysis*



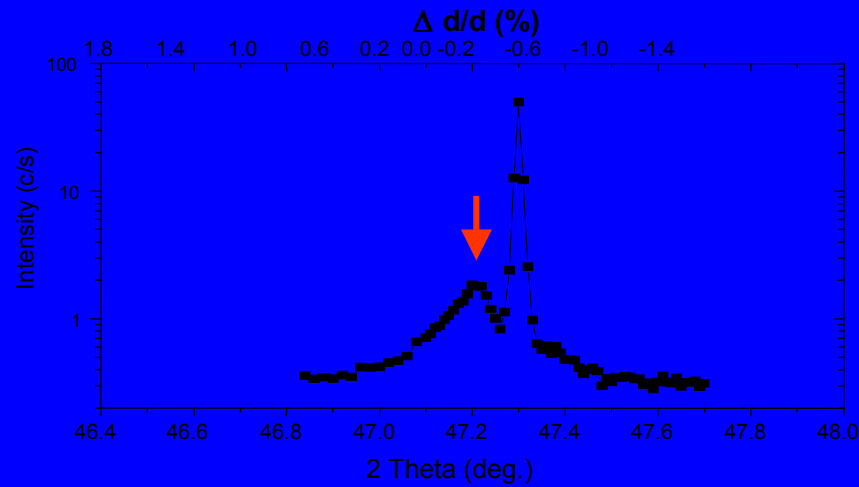
Si_{0.7}Ge_{0.3}/Si(100)

5nm

[110]



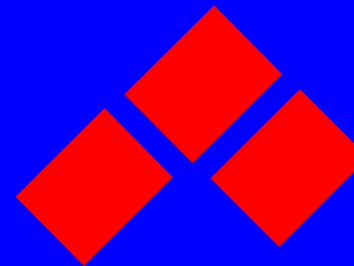
→ *No relaxation*



Si_{0.7}Ge_{0.3}/Si(100)

10nm

[110]



→ *Small relaxation (0.2%)*

($\Delta d/d \sim 1.2\%$ if total relaxation)

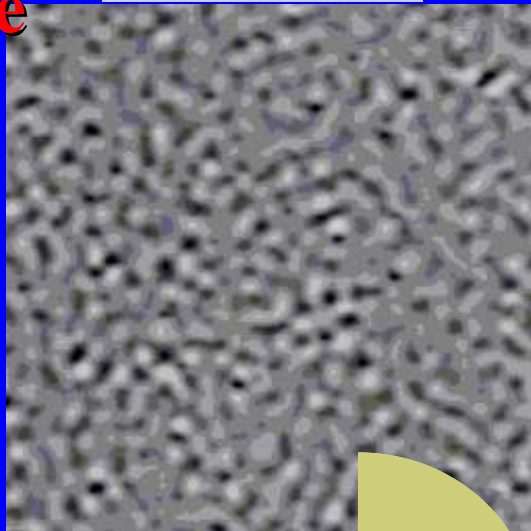
**Rough /
Ripple-like**

As grown

$x=0.25$

$m=1\%$

$h = 50\text{\AA}$

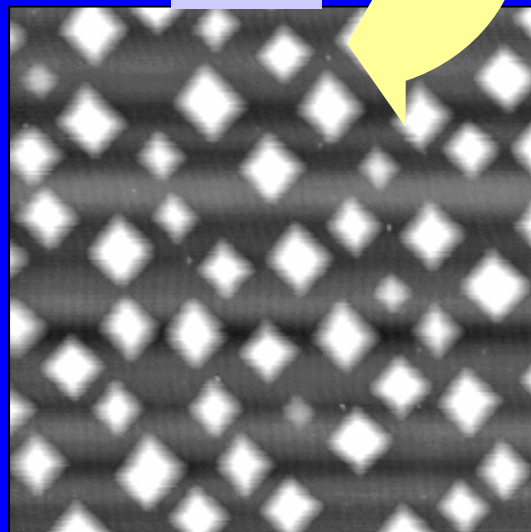


Scan : 5 μm

**Annealing 550°C
(1h30 - 18 h)**

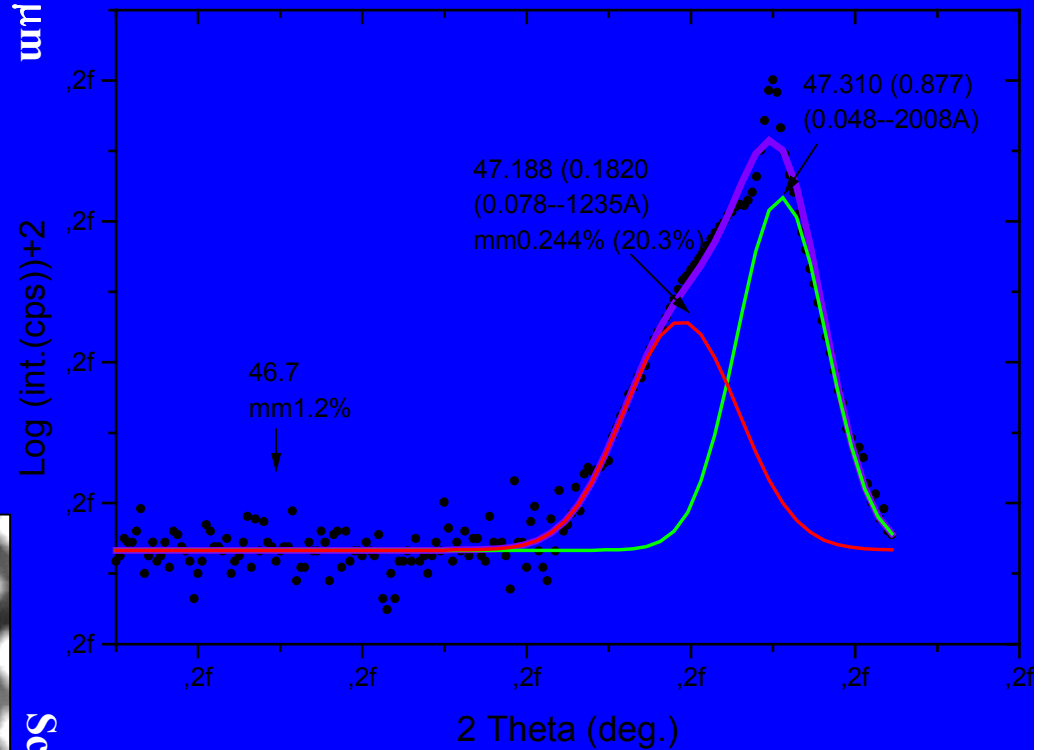
64 h

Huts



Scan : 2 μm

IMA122 (30%, 550°C-18h)

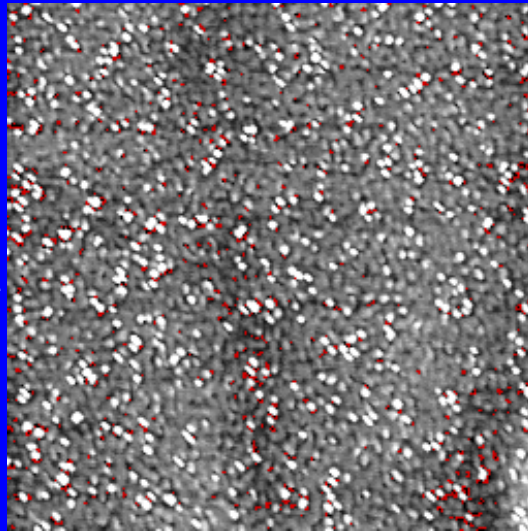
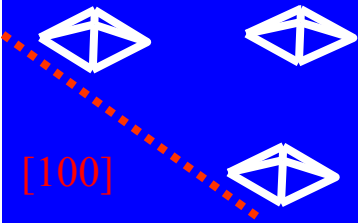


$\Delta\varepsilon = 0.25\%$

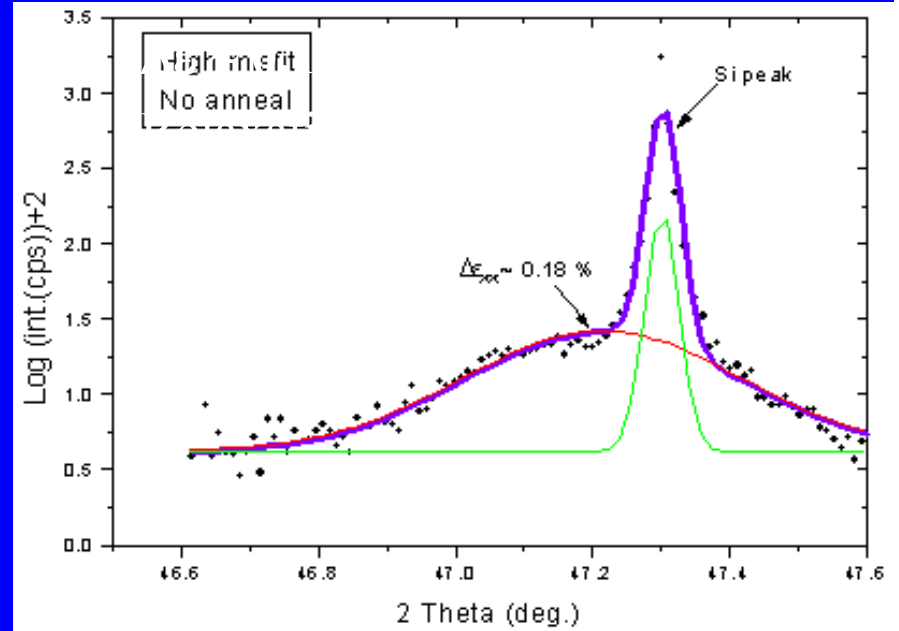
relaxation

Ilots « huttes » As grown

$x=0.4$
 $m=1.6\%$
 $h = 50\text{\AA}$

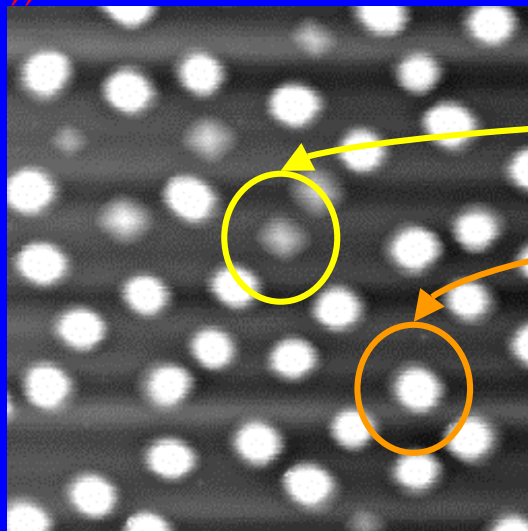
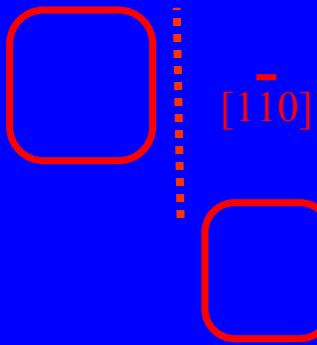


Scan : 5 μm

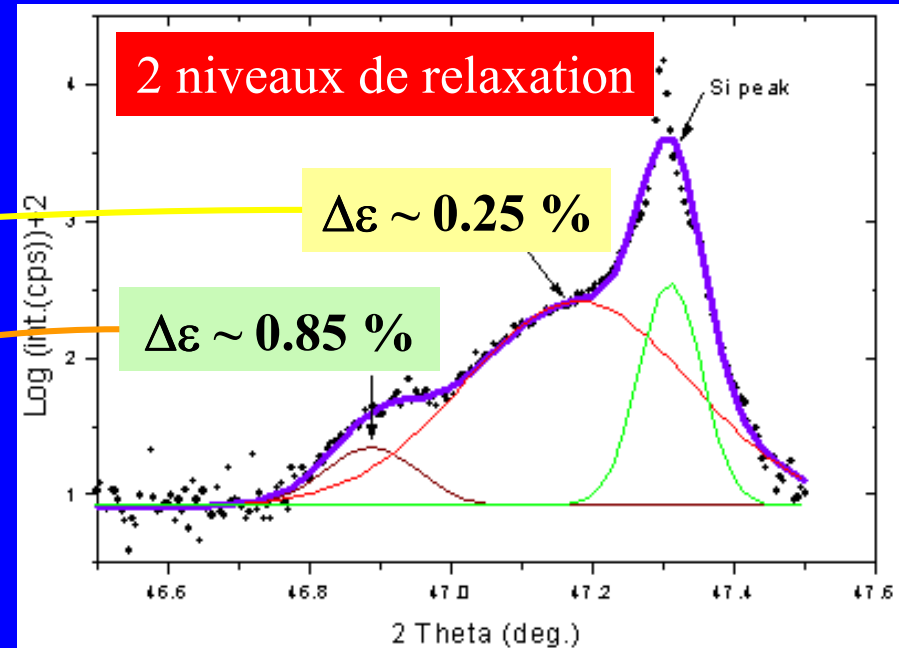


Recuit 550°C
 (1h → 18h)

Ilots « dômes »

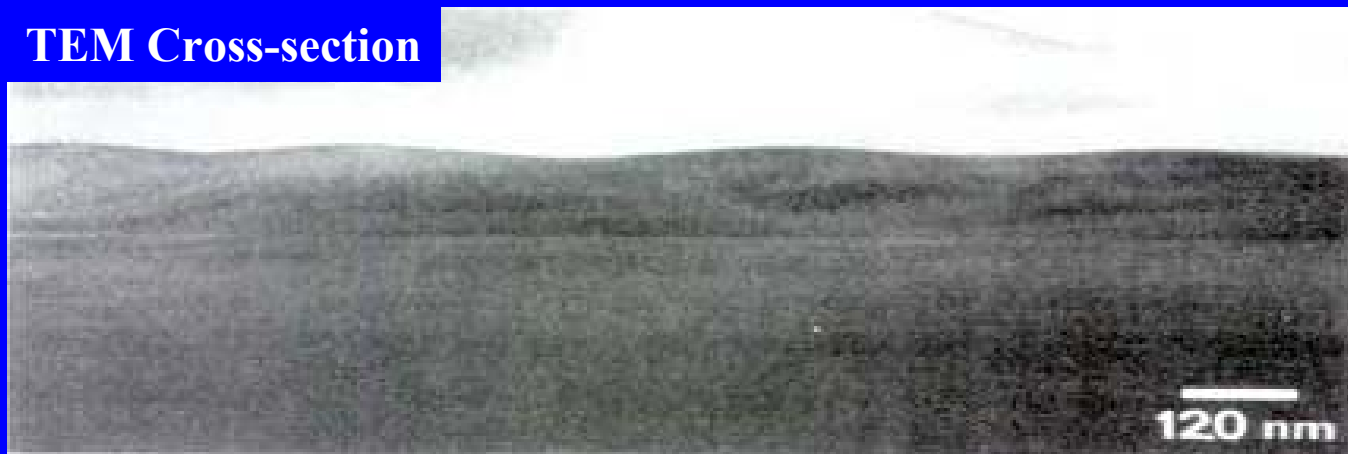


Facettes [113]

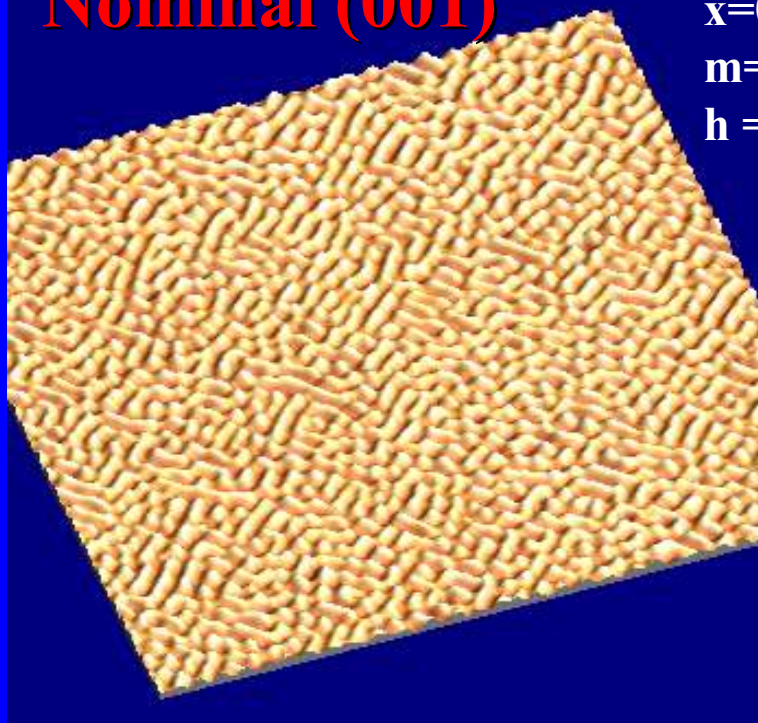


Influence of vicinal substrate

TEM Cross-section

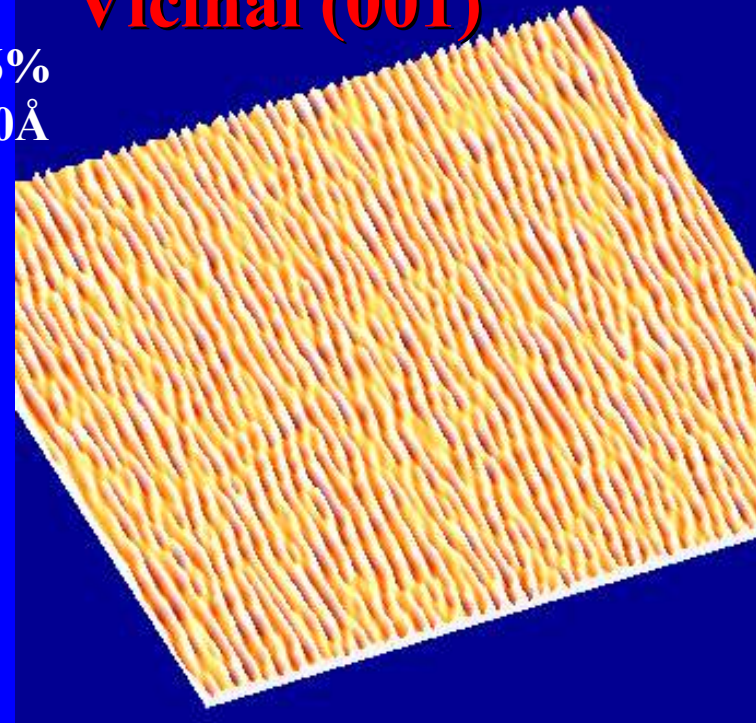


Nominal (001)



$x=0.4$
 $m=1.6\%$
 $h = 50\text{\AA}$

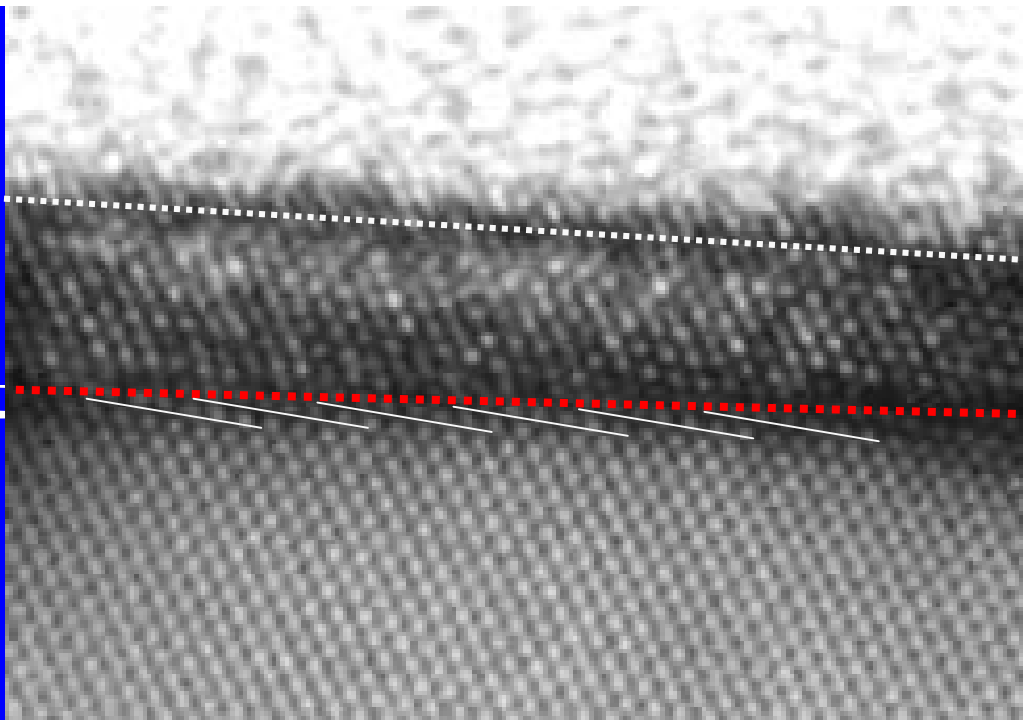
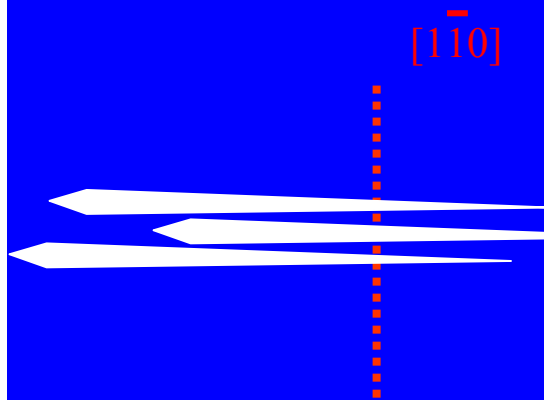
Vicinal (001)



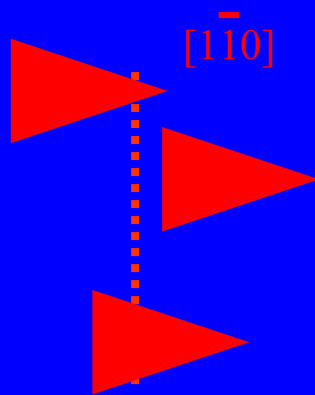
Scan : 5 μm

(118) Si = (001) 10° off

As grown

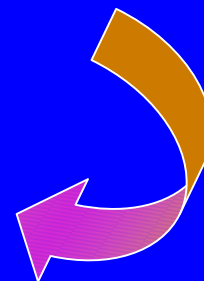
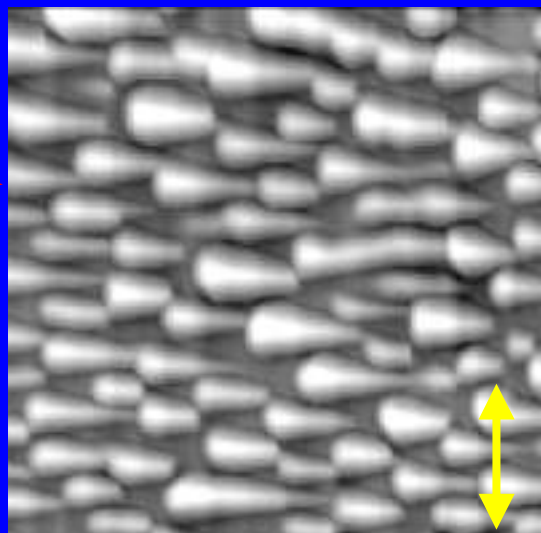


Annealed 550°C
(1h → 18h)



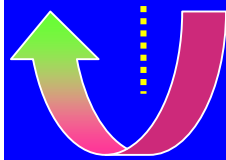
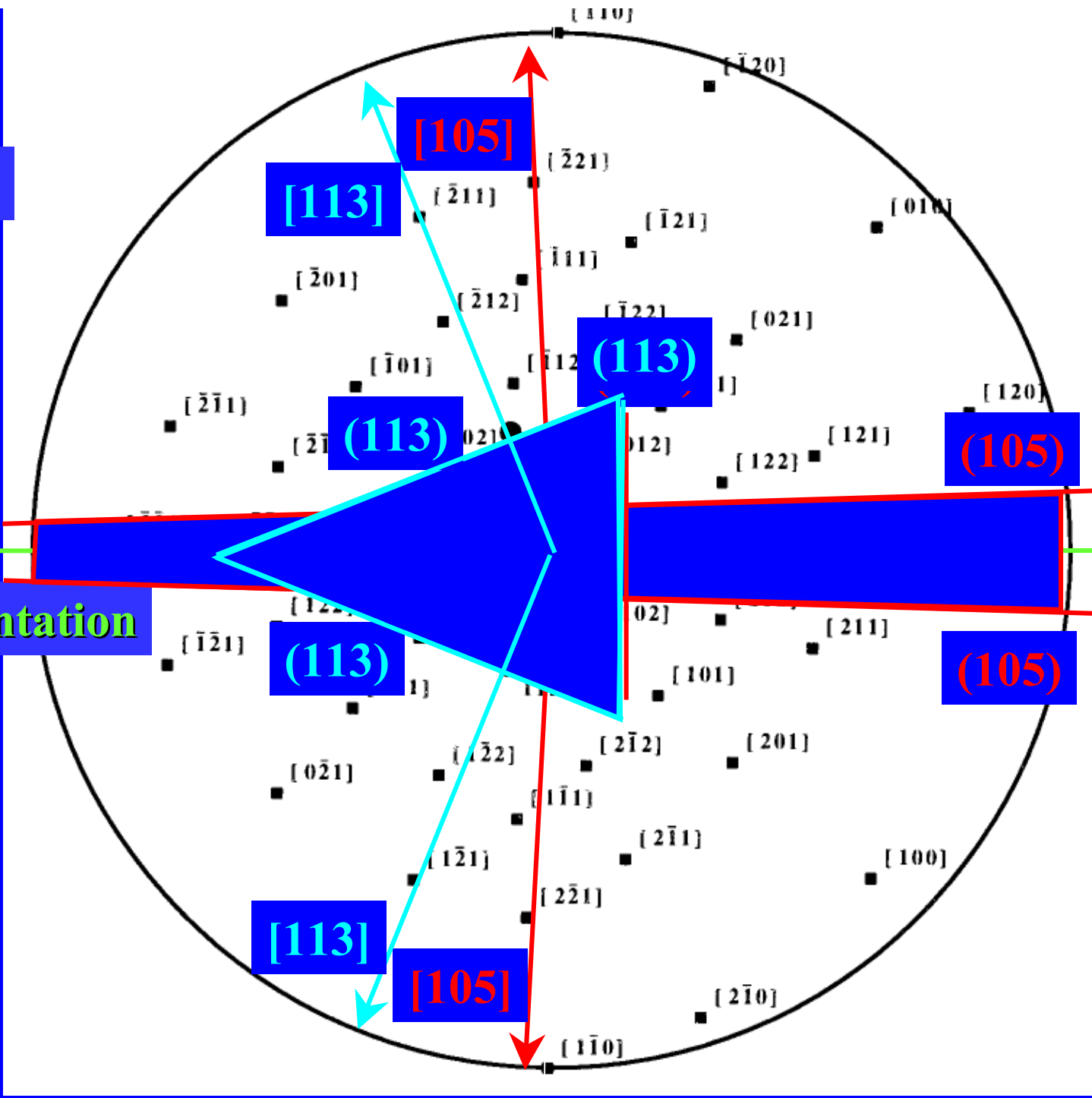
[113] facets

« Domes » islands



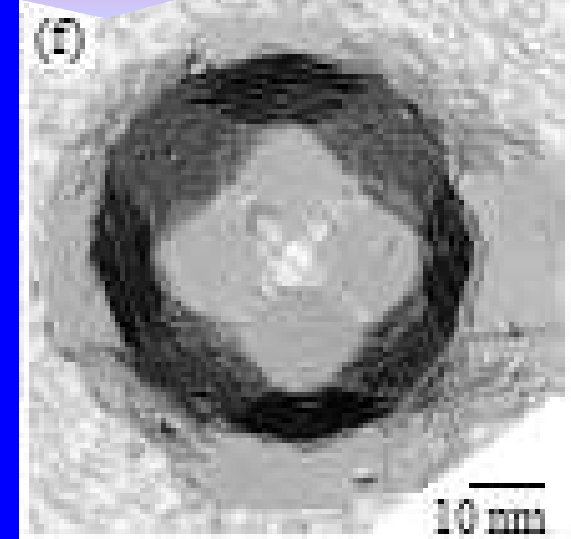
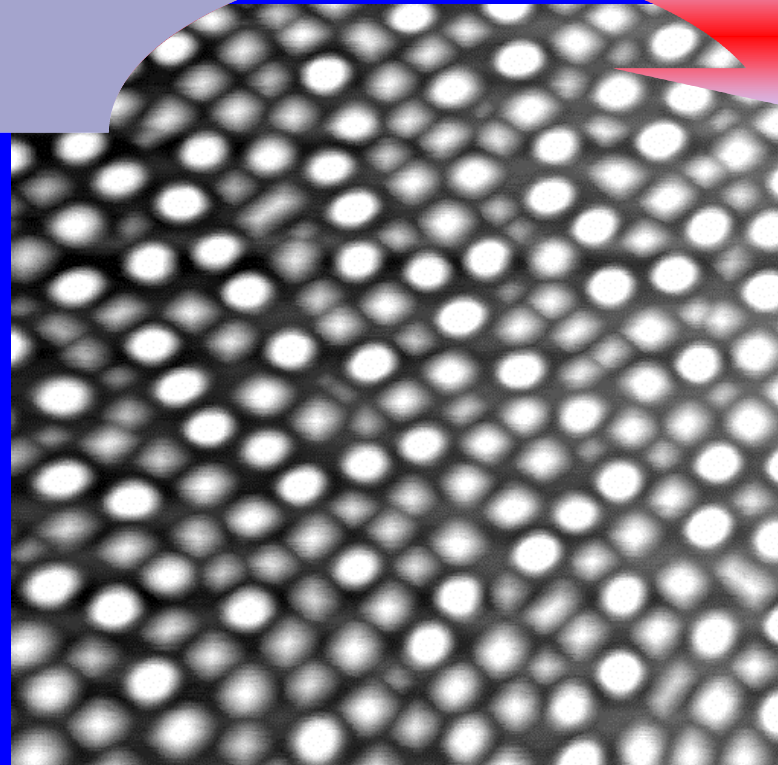
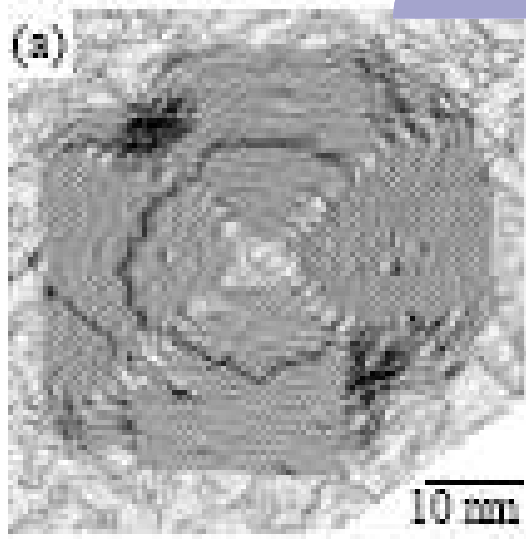
Marches

Désorientation



REGIME III: BIMODAL ISLANDS

Morphological shape transition



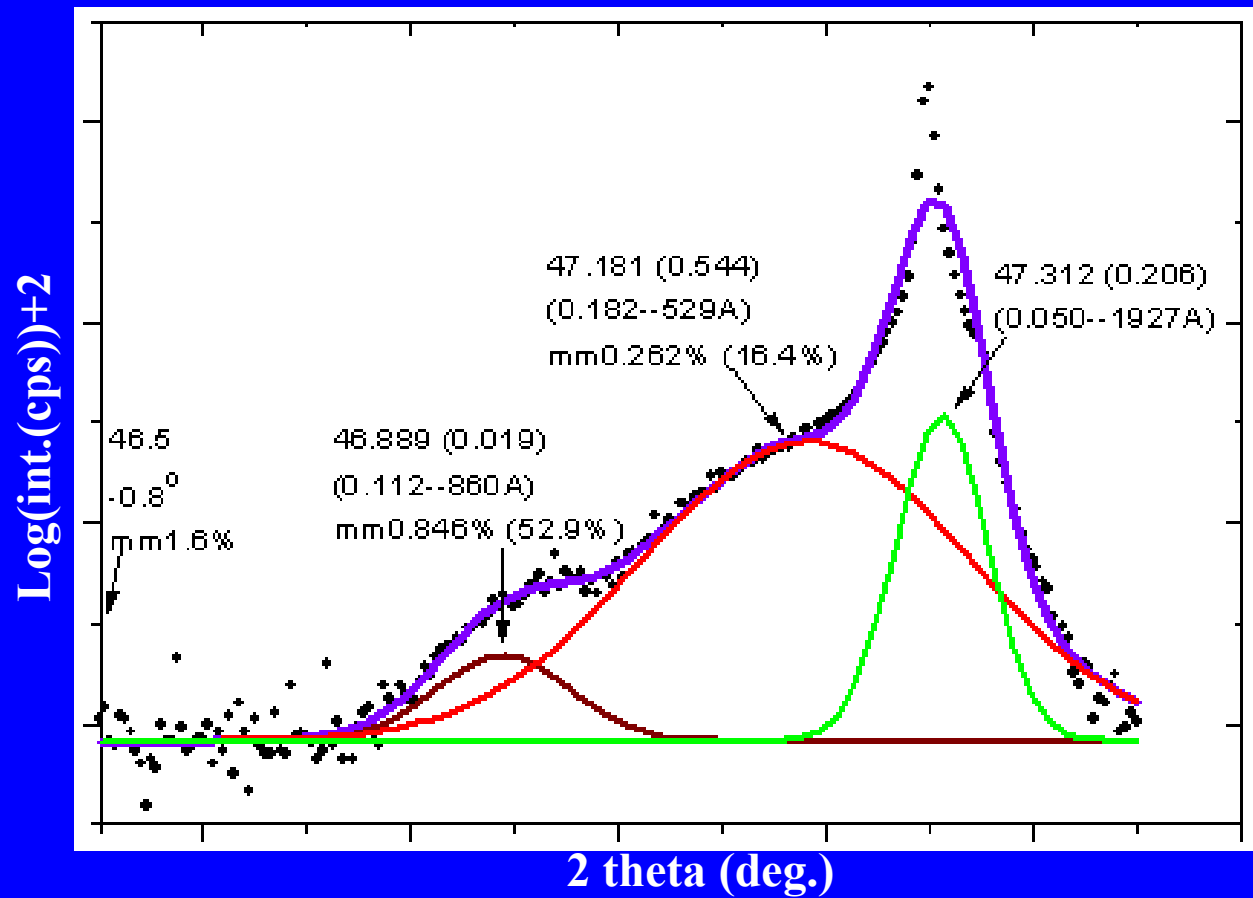
SiGe 35% 100 Å

Transition : Huts \Leftrightarrow Domes

Bimodal relaxation

Huts and Domes

0.25% and 0.85% relaxation



As grown

Annealing 550°C 18 h

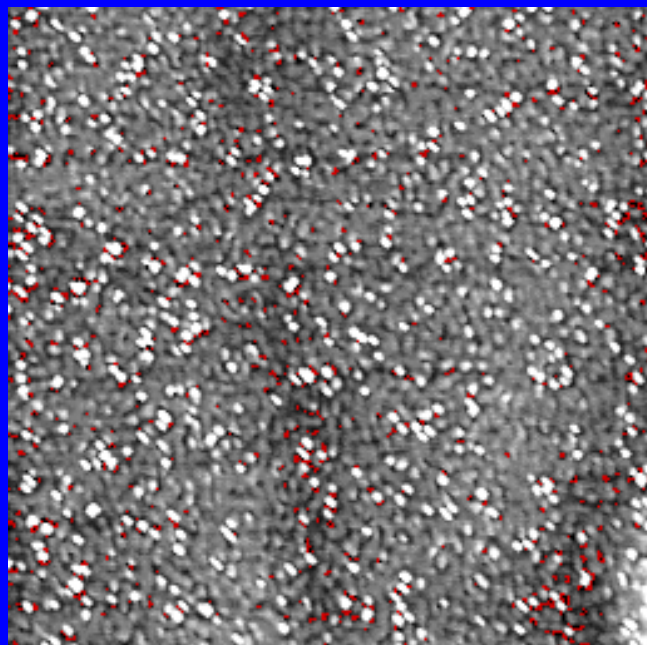
Huts

Huts + Domes

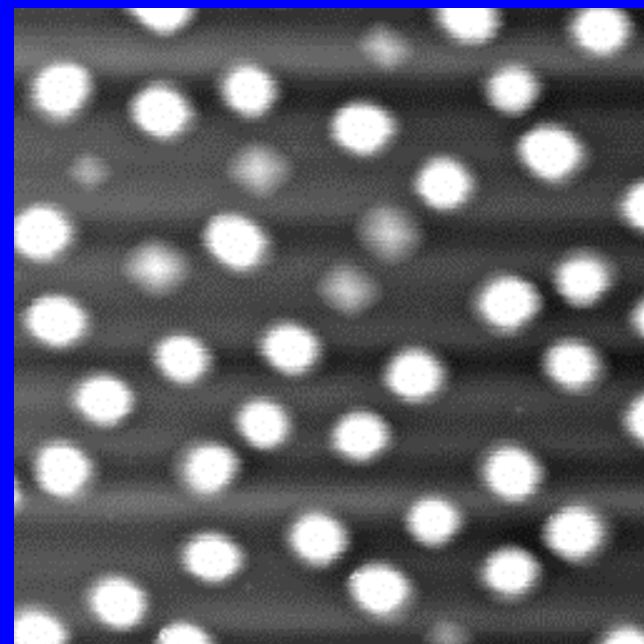
$x=0.4$

$m=1.6\%$

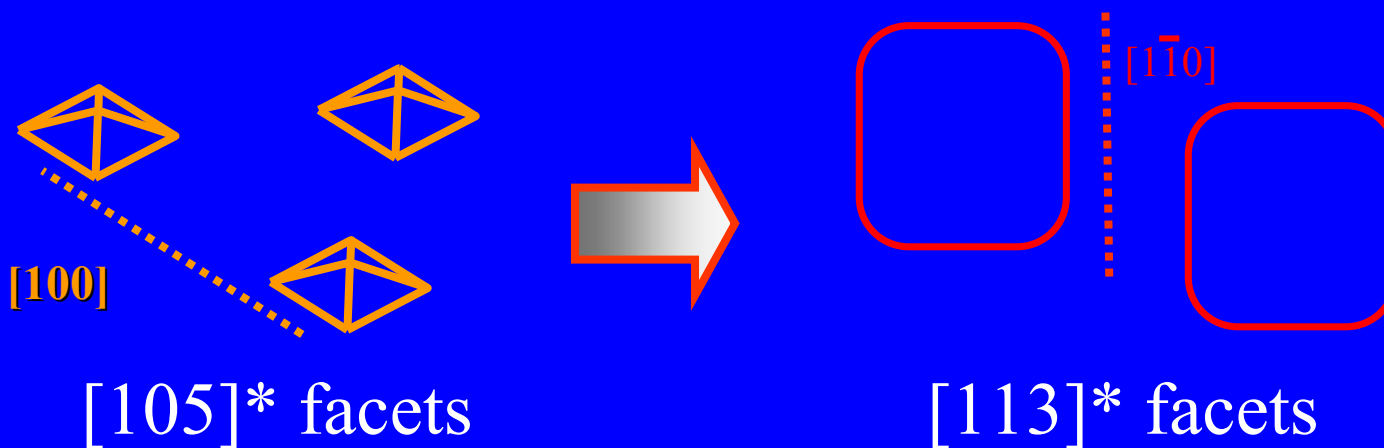
$h = 50\text{\AA}$



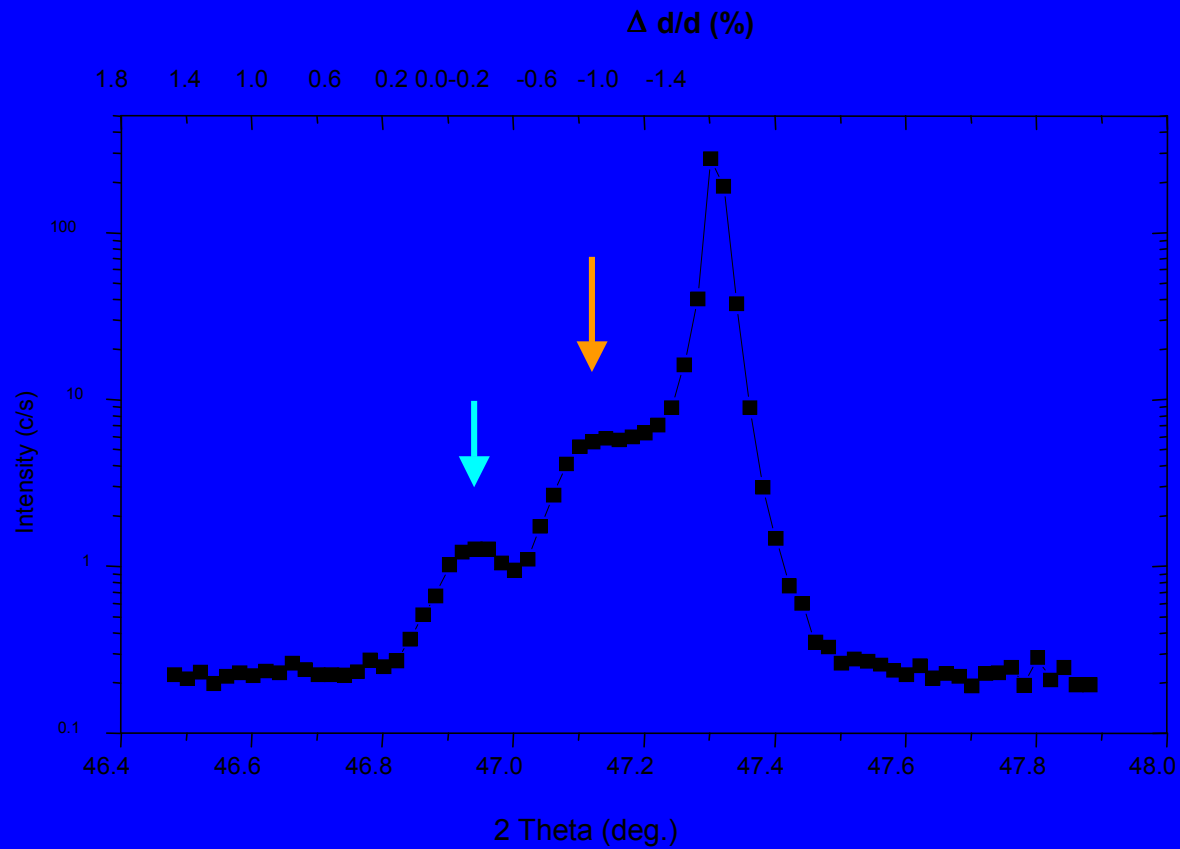
Scan : 5 μm



Scan : 2 μm



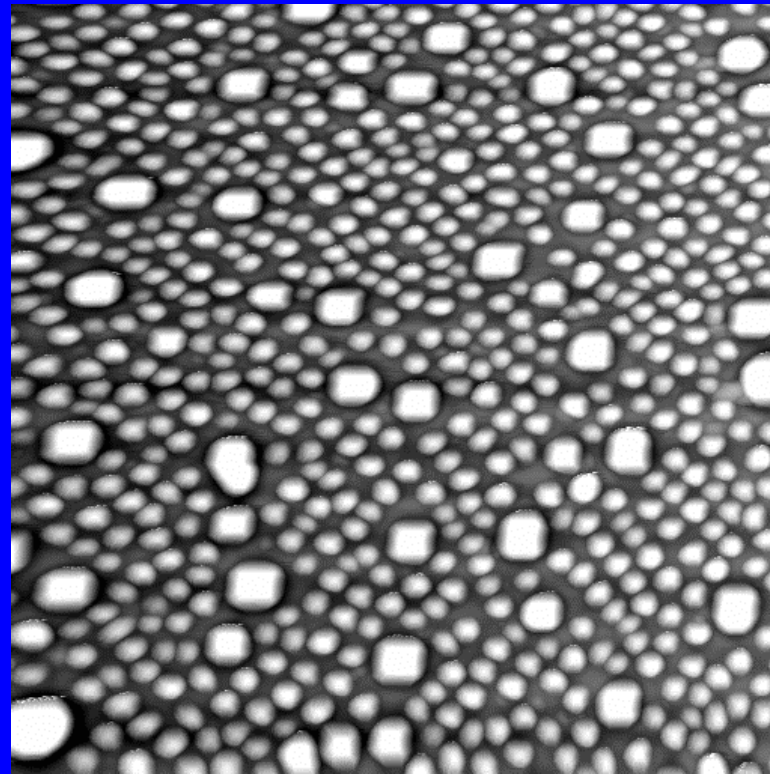
Stress Relaxation



Aspect ratio / Relaxation

REGIME IV: BIMODAL DOMES

Bimodal size distribution of Domes



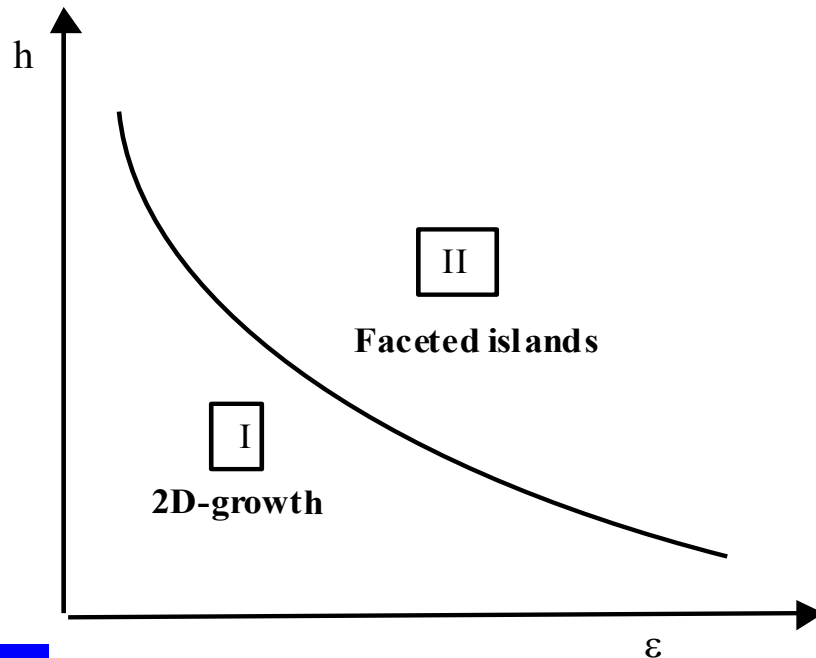
Scan : 20 μm

$x = 50\%$ $m = 2\%$ 150 \AA

Again 2 levels of relaxation

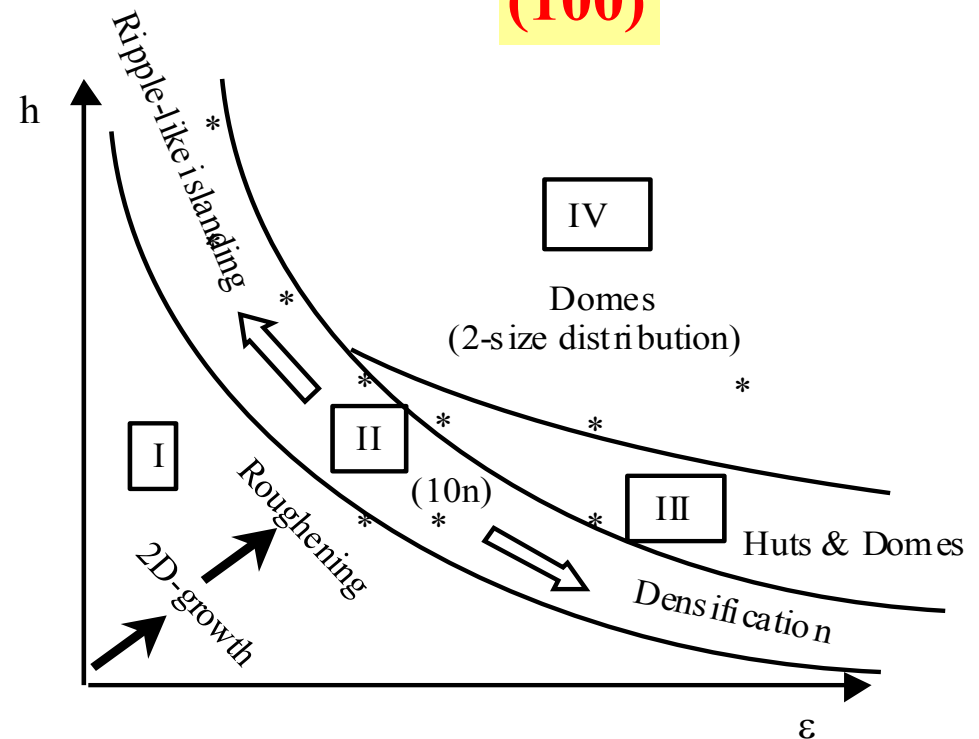
KINETIC PHASE DIAGRAMS

(111)



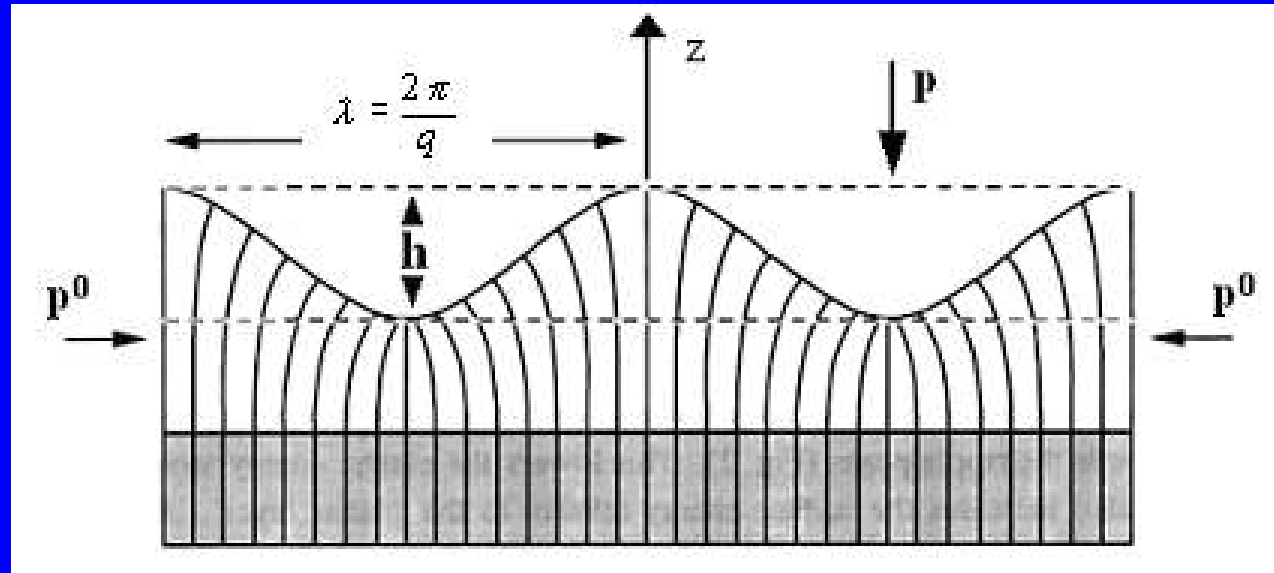
No kinetic instability
No strained islands

(100)



Regime II: growth instability
Regime III: islands
Morphological island transition
explained by stress relaxation

Stress driven instability ???



Total surface free energy :

Capillarity energy:

$$\frac{\partial F_{cap}}{\partial A} = \frac{\sigma}{4} h^2 q^2$$

Elastic relaxation :

$$\frac{\partial F_{relax}}{\partial A} \approx -h p^0 \varepsilon$$

Strain fields gradients

$$\frac{\partial F_{el}}{\partial A} \approx \frac{C \varepsilon^2}{2q}$$

Macroscopic strain models cannot explain :

- comparison (111) / (001)
- wires perpendicular to step edges

New model

SK on (001) \neq relaxation of elastic energy

BUT : SK instability does not form on Si(111)
Stabilisation of (105) facets under stress

- **Surface reconstruction** (MD et ab initio) Raiteri, Migas, Miglio, Phys Rev. Lett. (2002)

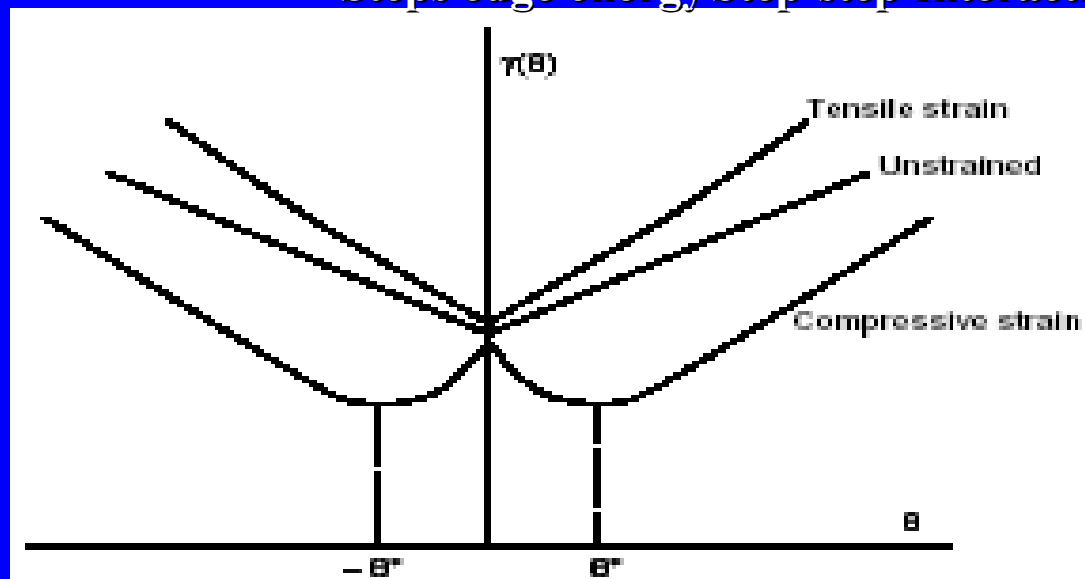
Balance elastic energy and facet energy

- **Surface energy of vicinal surface** (continuum model)

Tersoff Phys Rev. Lett.; Shenoy, Freund (2002)

$$\gamma(\theta) = \gamma_0 \cos\theta + \beta_1 |\sin\theta| + \beta_3 \frac{|\sin\theta|^3}{\cos^2\theta}$$

Steps edge energy Step-step Interaction



MORPHOLOGICAL EVOLUTION

Si(111): 2D layer by layer \Rightarrow 3D dislocated islands

THERMODYNAMIC EQUILIBRIUM SHAPE

Si(001) : 2D \Rightarrow instability \Rightarrow islanding \Rightarrow 3D dislocated islands
elongated islands \perp step deges

SURFACE ENERGY MINIMIZATION + KINETICS